

### 512K x 32 SRAM

### SRAM MEMORY ARRAY

### AVAILABLE AS MILITARY SPECIFICATIONS

- SMD 5962-94611 (Military Pinout)
- MIL-STD-883

### FEATURES

- Operation with single 5V supply
- High speed: 12, 15, 17, 20, 25 and 35ns
- Built in decoupling caps for low noise
- Organized as 512Kx32, byte selectable
- Low power CMOS
- TTL Compatible Inputs and Outputs
- Future offerings**  
3.3V Power Supply

### OPTIONS

- Operating Temperature Ranges
 

Military (-55°C to +125°C)	XT
Industrial (-40°C to +85°C)	IT

### Timing

12ns	-12
15ns	-15
17ns	-17
20ns	-20
25ns	-25
35ns	-35
45ns	-45
55ns	-55

### Package

Ceramic Quad Flatpack	Q
Ceramic Quad Flatpack	Q1
Ceramic Quad Flatpack	Q2
Pin Grid Array	P

- Low Power Data Retention Mode L

### Pinout

Military	(no indicator)
Commercial	A*

\*(available with Q package only)

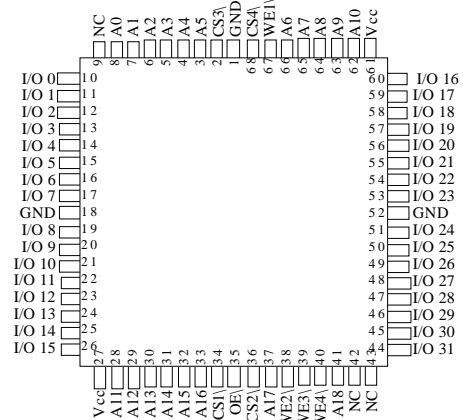
### GENERAL DESCRIPTION

The Austin Semiconductor, Inc. AS8S512K32 and AS8S512K32A are 16 Megabit CMOS SRAM Modules organized as 512Kx32 bits. These devices achieve high speed access, low power consumption and high reliability by employing advanced CMOS memory technology.

This military temperature grade product is ideally suited for military and space applications.

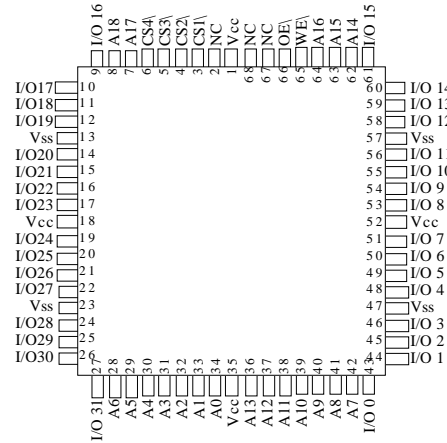
### PIN ASSIGNMENT (Top View)

68 Lead CQFP (Q, Q1 & Q2)  
Military SMD Pinout Option



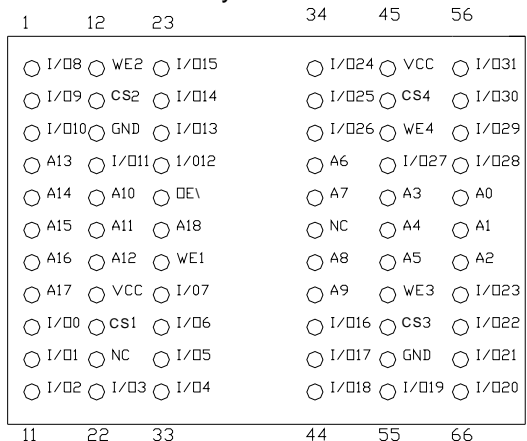
### 68 Lead CQFP

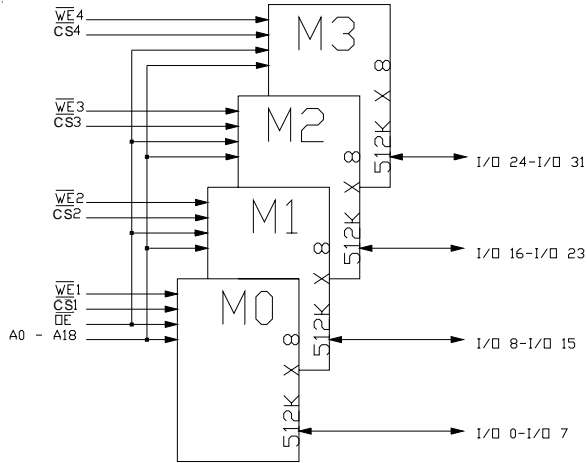
Commercial Pinout Option (Q & Q1 with A)



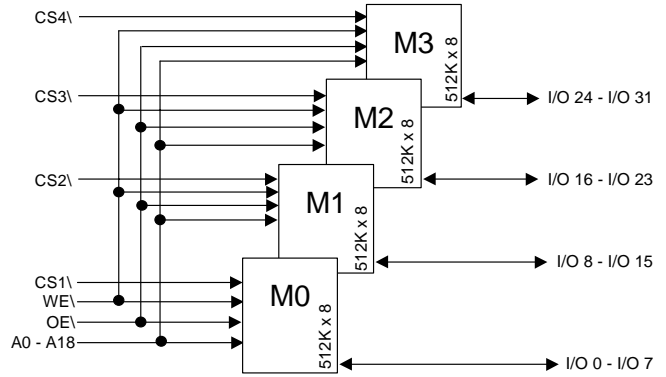
### 66 Lead PGA (P)

Military SMD Pinout





MILITARY PINOUT/BLOCK DIAGRAM



COMMERCIAL PINOUT/BLOCK DIAGRAM

**TRUTH TABLE**

MODE	OE $\setminus$	CS $\setminus$	WE $\setminus$	I/O	POWER
Read	L	L	H	D <sub>OUT</sub>	ACTIVE
Write	X	L	L	D <sub>IN</sub>	ACTIVE
Standby	X	H	X	High Z	STANDBY



**ABSOLUTE MAXIMUM RATINGS\***

Voltage of Vcc Supply Relative to Vss.....-5V to +7V  
 Storage Temperature.....-65°C to +150°C  
 Short Circuit Output Current(per I/O).....20mA  
 Voltage on Any Pin Relative to Vss.....-5V to Vcc+1V  
 Maximum Junction Temperature\*\* .....+150°C

\*Stresses greater than those listed under “Absolute Maximum Ratings” may cause permanent damage to the device.

This is a stress rating only and functional operation on the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

\*\*Junction temperature depends upon package type, cycle time, loading, ambient temperature and airflow. See the Application Information section at the end of this datasheet for more information.

**ELECTRICAL CHARACTERISTICS AND RECOMMENDED DC OPERATING CONDITIONS**

(-55°C ≤ T<sub>A</sub> ≤ 125°C and -40°C to +85°C; Vcc = 5V ±10%)

DESCRIPTION	CONDITIONS	SYMBOL	MIN	MAX	UNITS	NOTES
Input High (logic 1) Voltage		V <sub>IH</sub>	2.2	V <sub>CC</sub> +0.5	V	1
Input Low (logic 1) Voltage		V <sub>IL</sub>	-0.5	0.8	V	1,2
Input Leakage Current <sub>ADD,OE</sub>	0V < V <sub>IN</sub> < V <sub>CC</sub>	I <sub>LI1</sub>	-10	10	μA	
Input Leakage Current <sub>WE, CE</sub>		I <sub>LI2</sub>	-10	10	μA	
Output Leakage Current <sub>I/O</sub>	Output(s) Disabled 0V < V <sub>OUT</sub> < V <sub>CC</sub>	I <sub>LO</sub>	-10	10	μA	
Output High Voltage	I <sub>OH</sub> = -4.0mA	V <sub>OH</sub>	2.4		V	1
Output Low Voltage	I <sub>OL</sub> = 8.0mA	V <sub>OL</sub>		0.4	V	1
Supply Voltage		V <sub>CC</sub>	4.5	5.5	V	1

DESCRIPTION	CONDITIONS	SYMBOL	MAX								UNITS	NOTES
			-12	-15	-17	-20	-25	-35	-45	-55		
Power Supply Current: Operating	CS\<V <sub>IL</sub> ; V <sub>CC</sub> = MAX f = MAX = 1/ tRC (MIN) Outputs Open	I <sub>CC</sub>	250	200	700	650	600	570	570	550	mA	3,13
Power Supply Current: Standby	CS\>V <sub>IH</sub> ; V <sub>CC</sub> = MAX f = MAX = 1/ tRC (MIN) Outputs Open	I <sub>SBT1</sub>	80	80	240	240	190	190	150	150	mA	3, 13
CMOS Standby	V <sub>IN</sub> = V <sub>CC</sub> - 0.2V, or V <sub>SS</sub> +0.2V V <sub>CC</sub> =Max; f = 0Hz	I <sub>SBT2</sub>	80	80	80	80	80	80	80	80	mA	

**CAPACITANCE** ( $V_{IN} = 0V, f = 1MHz, T_A = 25^{\circ}C$ )<sup>1</sup>

SYMBOL	PARAMETER	MAX	UNITS
$C_{ADD}$	A0 - A18 Capacitance	50	pF
$C_{OE}$	OE\ Capacitance	50	pF
$C_{WE}, C_{CS}$	WE\ and CS\ Capacitance	20	pF
$C_{IO}$	I/O 0- I/O 31 Capacitance	20	pF
$C_{WE}$ ("A" version)	WE\ Capacitance	50	pF

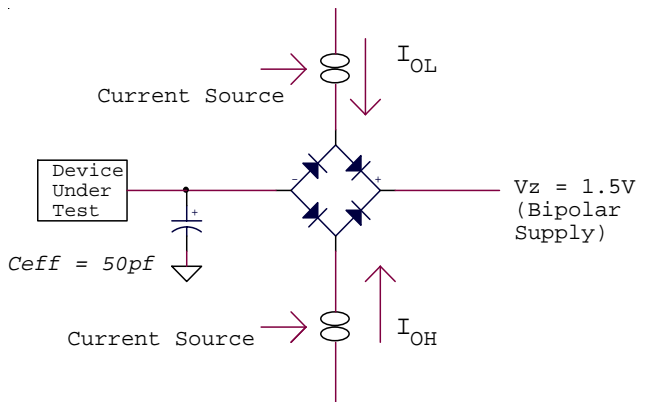
**NOTE:**

1. This parameter is sampled.

**AC TEST CONDITIONS**

**Test Specifications**

Input pulse levels.....VSS to 3V  
 Input rise and fall times.....5ns  
 Input timing reference levels.....1.5V  
 Output reference levels.....1.5V  
 Output load.....See Figure 1



**Figure 1**

**NOTES:**

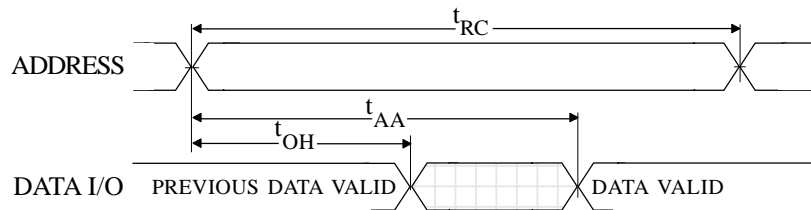
- $V_z$  is programmable from -2V to +7V.
- $I_{OL}$  and  $I_{OH}$  programmable from 0 to 16 mA.
- $V_z$  is typically the midpoint of  $V_{OH}$  and  $V_{OL}$ .
- $I_{OL}$  and  $I_{OH}$  are adjusted to simulate a typical resistive load circuit.



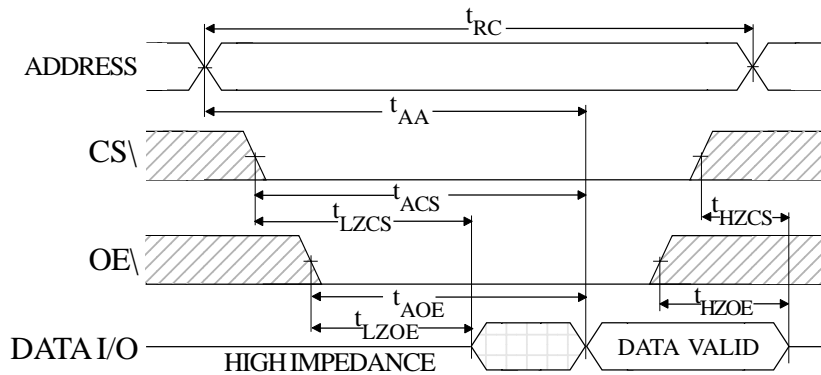
**ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS**  
(NOTE 5) (-55°C ≤ T<sub>A</sub> ≤ 125°C and -40°C to +85°C; V<sub>CC</sub> = 5V ±10%)

DESCRIPTION	SYMBOL	-12		-15		-17		-20		-25		-35		-45		-55		UNITS	NOTES
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
<b>READ CYCLE</b>																			
READ cycle time	t <sub>RC</sub>	12		15		17		20		25		35		45		55		ns	
Address access time	t <sub>AA</sub>		12		15		17		20		25		35		45		55	ns	
Chip select access time	t <sub>ACS</sub>		12		15		17		20		25		35		45		55	ns	
Output hold from address change	t <sub>OH</sub>	2		2		2		2		2		2		2		2		ns	
Chip select to output in Low-Z	t <sub>LZCS</sub>	2		2		2		2		2		2		2		2		ns	4,6,7
Chip select to output in High-Z	t <sub>HZCS</sub>		7		8		9		10		12		15		20		20	ns	4,6,7
Output enable access time	t <sub>AOE</sub>		7		8		9		10		12		15		20		20	ns	
Output enable to output in Low-Z	t <sub>LZOE</sub>	0		0		0		0		0		0		0		0		ns	4,6
Output disable to output in High-Z	t <sub>HZOE</sub>						12		12		12		15		20		20	ns	4,6
<b>WRITE CYCLE</b>																			
WRITE cycle time	t <sub>WC</sub>	12		15		17		20		25		35		45		55		ns	
Chip select to end of write	t <sub>CW</sub>	10		12		15		15		17		20		25		25		ns	
Address valid to end of write	t <sub>AW</sub>	10		12		15		15		17		20		25		25		ns	
Address setup time	t <sub>AS</sub>	2		2		2		2		2		2		2		2		ns	
Address hold from end of write	t <sub>AH</sub>	1		1		1		1		1		1		1		1		ns	
WRITE pulse width	t <sub>WP1</sub>	10		12		15		15		17		20		25		25		ns	
WRITE pulse width	t <sub>WP2</sub>	10		12		15		15		17		20		25		25		ns	
Data setup time	t <sub>DS</sub>	8		10		12		10		12		15		20		20		ns	
Data hold time	t <sub>DH</sub>	0		0		0		0		0		0		0		0		ns	
Write disable to output in Low-z	t <sub>LZWE</sub>	2		2		2		2		2		2		2		2		ns	4,6,7
Write enable to output in High-Z	t <sub>HZWE</sub>	7		8			9		11		13		15		15		15	ns	4,6,7

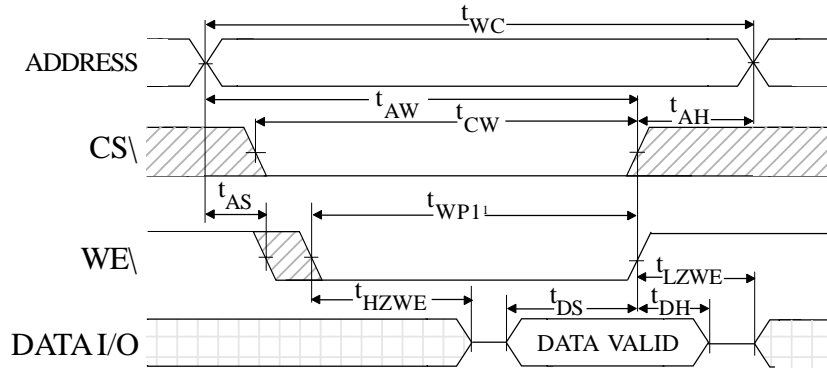
**READ CYCLE NO. 1**



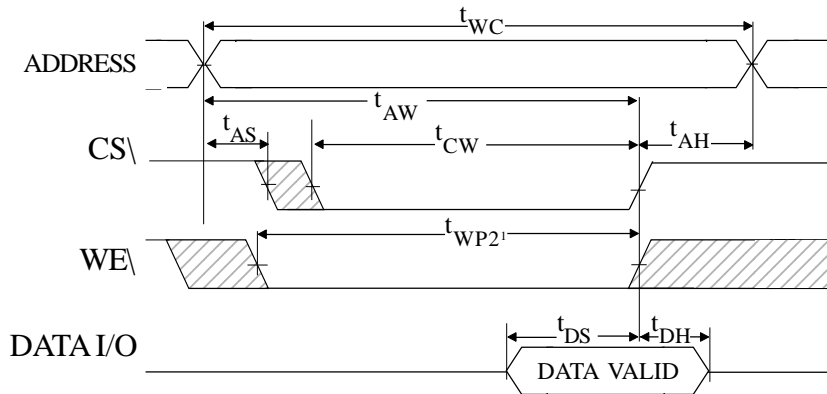
**READ CYCLE NO. 2**



**WRITE CYCLE NO. 1**  
(Chip Select Controlled)



**WRITE CYCLE NO. 2**  
(Write Enable Controlled)



**NOTES**

1. All voltages referenced to  $V_{SS}$  (GND).
2. -2V for pulse width <20ns.
3.  $I_{CC}$  is dependent on output loading and cycle rates.

$$\text{unloaded, and } f = \frac{1}{t_{RC(MIN)}} \text{ Hz.}$$

The specified value applies with the outputs

4. This parameter guaranteed but not tested.
5. Test conditions as specified with output loading as shown in Fig. 1 unless otherwise noted.
6.  $t_{HZCS}$ ,  $t_{HZOE}$  and  $t_{HZWE}$  are specified with  $C_L = 5\text{pF}$  as in Fig. 2. Transition is measured +/- 200 mV typical from steady state voltage, allowing for actual tester RC time constant.

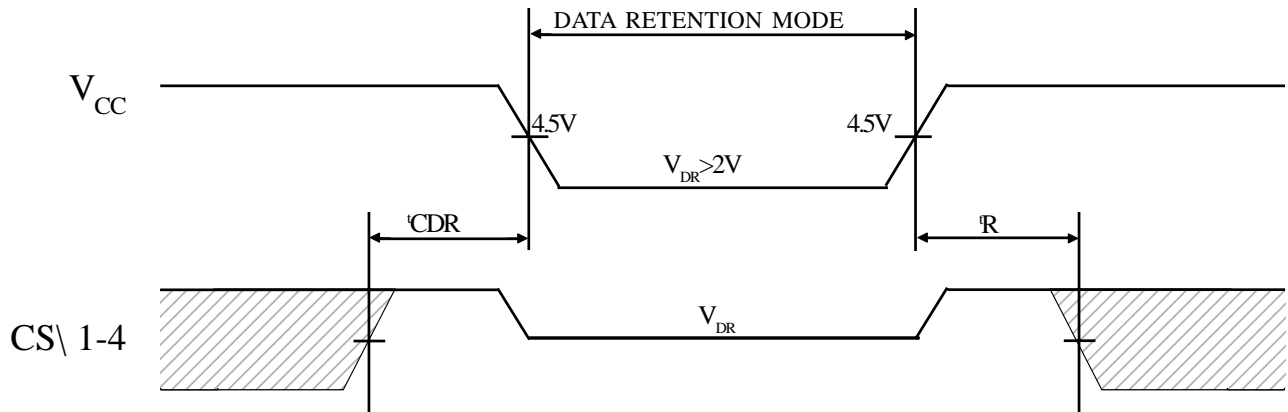
7. At any given temperature and voltage condition,  $t_{HZCS}$  is less than  $t_{LZCS}$ , and  $t_{HZWE}$  is less than  $t_{LZWE}$ .
8.  $WE\backslash$  is HIGH for READ cycle.
9. Device is continuously selected. Chip selects and output enable are held in their active state.
10. Address valid prior to or coincident with latest occurring chip enable.
11.  $t_{RC}$  = READ cycle time.
12. Chip enable ( $CS\backslash$ ) and write enable ( $WE\backslash$ ) can initiate and terminate a WRITE cycle.
13.  $I_{CC}$  is for 32 bit mode.

**LOW POWER CHARACTERISTICS (L Version Only)**

DESCRIPTION	CONDITIONS	SYMBOL	MIN	MAX	UNITS	NOTES
$V_{CC}$ for Retention Data		$V_{DR}$	2		V	
Data Retention Current	All Inputs @ $V_{CC} \pm 0.2V$ or $V_{SS} \pm 0.2V$ , $CS\backslash = V_{CC} \pm 0.2V$	$V_{CC} = 2V$		20	mA	
		$V_{CC} = 3V$		28*	mA	
Chip Deselect to Data Retention Time		$t_{CDR}$	0		ns	4
Operation Recovery Time		$t_R$	$t_{RC}$		ns	4, 11

\* -12 and -15 have a 32mA limit.

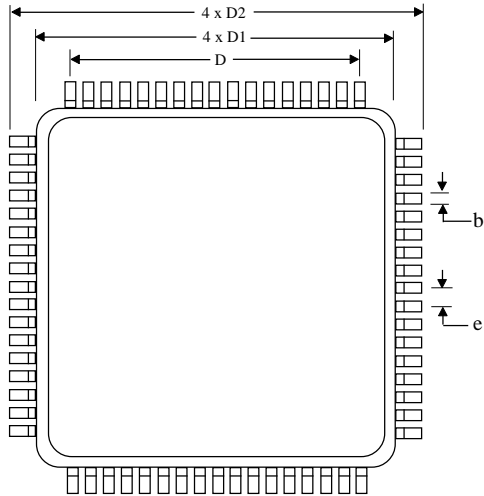
**LOW  $V_{CC}$  DATA RETENTION WAVEFORM**



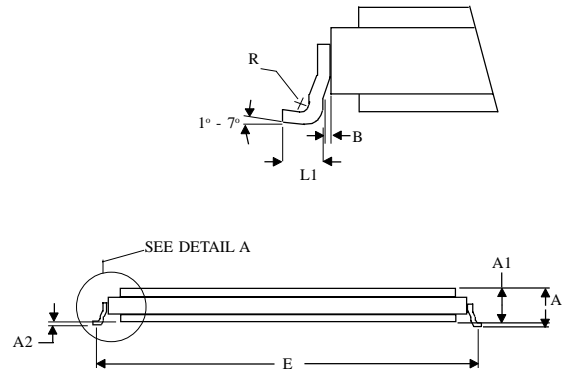


**MECHANICAL DEFINITIONS\***

ASI Case #702 (Package Designator Q)  
SMD 5962-94611, Case Outline M



DETAIL A

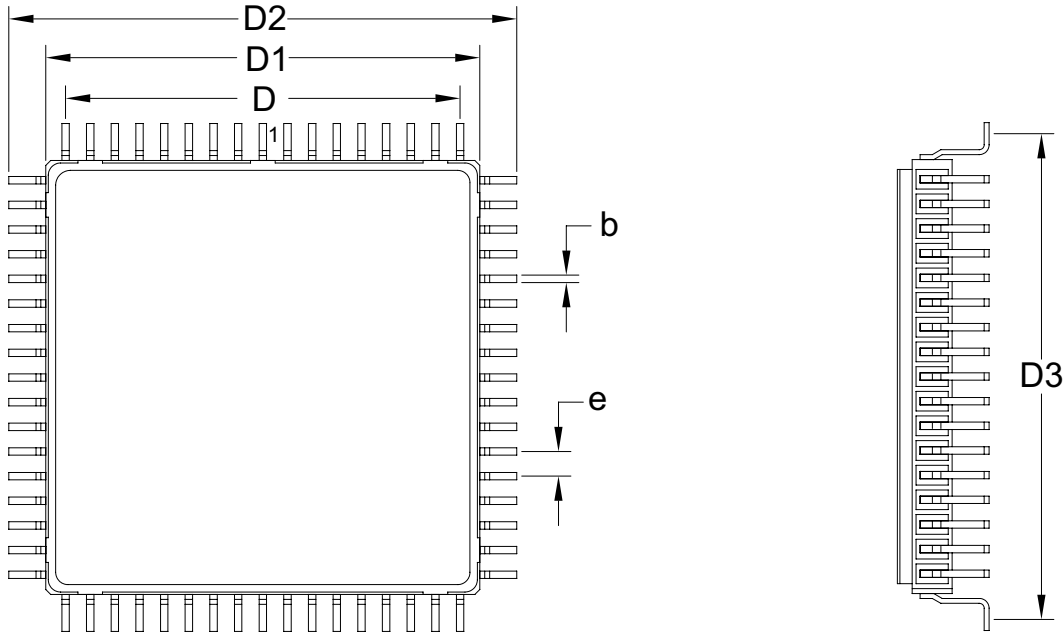


SYMBOL	SMD SPECIFICATIONS	
	MIN	MAX
A	0.123	0.200
A1	0.118	0.186
A2	0.000	0.020
B	0.010 REF	
b	0.013	0.017
D	0.800 BSC	
D1	0.870	0.890
D2	0.980	1.000
E	0.936	0.956
e	0.050 BSC	
R	0.005	---
L1	0.035	0.045

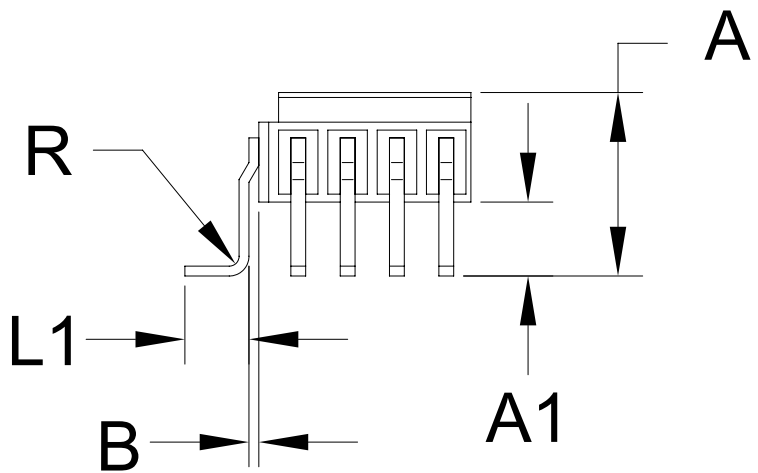
\*All measurements are in inches.

**MECHANICAL DEFINITIONS\***

ASI Package Designator Q2



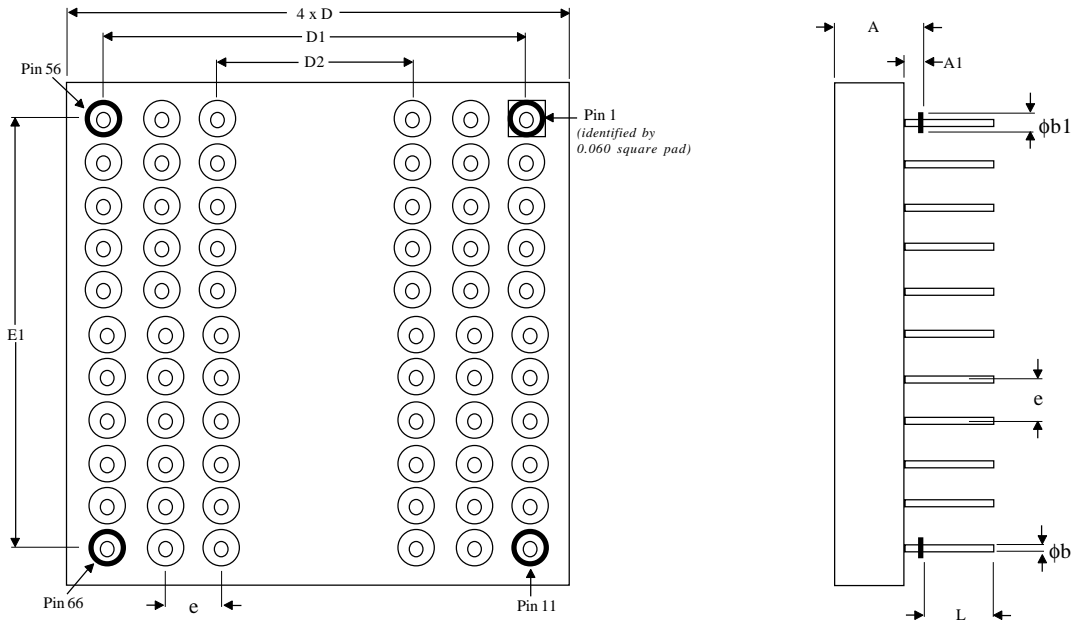
ASI PACKAGE SPECIFICATION		
Symbol	Min	Max
A		.200
A1	.070	.080
b	.013	.017
B	.010 REF	
D	.800 BSC	
D1	.870	.890
D2	1.010	1.030
D3	.975	.995
e	.050 BSC	
R	.010 TYP	
L1	.050	.065
Dimensions in inches		



\*All measurements are in inches.

## MECHANICAL DEFINITIONS\*

ASI Case #904 (Package Designator P )  
SMD 5962-94611, Case Outline T

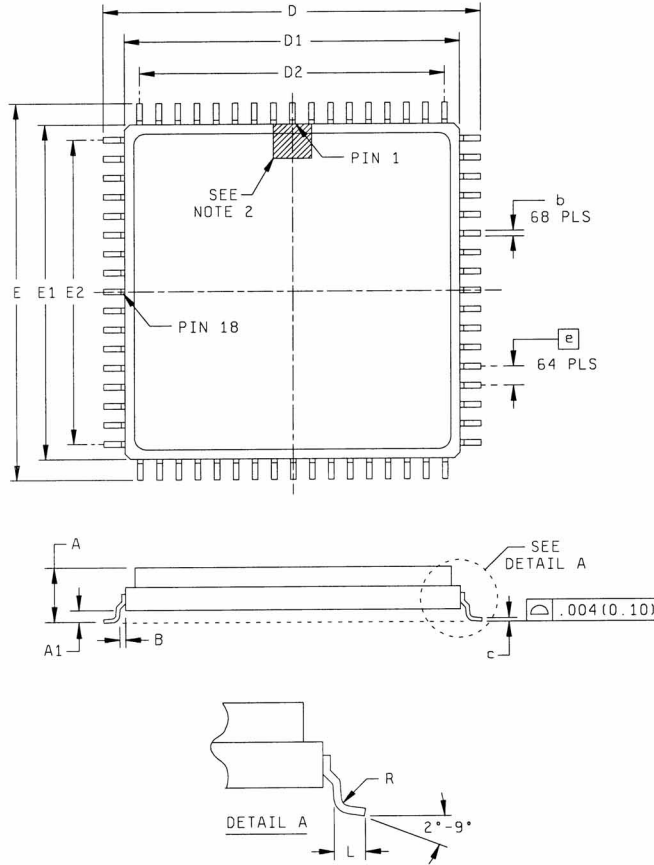


SYMBOL	SMD SPECIFICATIONS	
	MIN	MAX
A	0.144	0.181
A1	0.025	0.035
$\phi b$	0.016	0.020
$\phi b1$	0.045	0.055
D	1.065	1.085
D1/E1	1.000 TYP	
D2	0.600 TYP	
e	0.100 TYP	
L	0.145	0.155

\*All measurements are in inches.

## MECHANICAL DEFINITIONS\*

ASI Case (Package Designator Q1)  
 SMD 5962-94611, Case Outline A



SYMBOL	SMD SPECIFICATIONS	
	MIN	MAX
A	---	0.200
A1	0.054	---
b	0.013	0.017
B	0.010 TYP	
c	0.009	0.012
D/E	0.980	1.000
D1/E1	0.870	0.890
D2/E2	0.800 BSC	
e	0.050 BSC	
L	0.035	0.045
R	0.010 TYP	

\*All measurements are in inches.



## ORDERING INFORMATION

**EXAMPLE:** AS8S512K32Q-15/883C

Device Number	Package Type	Speed ns	Options**	Process
AS8S512K32	Q	-12		/*
AS8S512K32	Q	-15		/*
AS8S512K32	Q	-17		/*
AS8S512K32	Q	-20		/*
AS8S512K32	Q	-25		/*
AS8S512K32	Q	-35		/*
AS8S512K32	Q	-45		/*
AS8S512K32	Q	-55		/*

**EXAMPLE:** AS8S512K32Q1-55/IT

Device Number	Options**	Package Type	Speed ns	Process
AS8S512K32		Q1	-12	/*
AS8S512K32		Q1	-15	/*
AS8S512K32		Q1	-17	/*
AS8S512K32		Q1	-20	/*
AS8S512K32		Q1	-25	/*
AS8S512K32		Q1	-35	/*
AS8S512K32		Q1	-45	/*
AS8S512K32		Q1	-55	/*

**EXAMPLE:** AS8S512K32P-25L/XT

Device Number	Package Type	Speed ns	Options**	Process
AS8S512K32	P	-12		/*
AS8S512K32	P	-15		/*
AS8S512K32	P	-17		/*
AS8S512K32	P	-20		/*
AS8S512K32	P	-25		/*
AS8S512K32	P	-35		/*
AS8S512K32	P	-45		/*
AS8S512K32	P	-55		/*

**EXAMPLE:** AS8S512K32Q2-35L/XT

Device Number	Options**	Package Type	Speed ns	Process
AS8S512K32		Q2	-12	/*
AS8S512K32		Q2	-15	/*
AS8S512K32		Q2	-17	/*
AS8S512K32		Q2	-20	/*
AS8S512K32		Q2	-25	/*
AS8S512K32		Q2	-35	/*
AS8S512K32		Q2	-45	/*
AS8S512K32		Q2	-55	/*

### \*AVAILABLE PROCESSES

IT = Industrial Temperature Range	-40°C to +85°C
XT = Extended Temperature Range	-55°C to +125°C
Q = Full Military Processing	-55°C to +125°C
SPACE= Class K Equivalent	-55°C to +125°C

### \*\*DEFINITION OF OPTIONS

no indicator = Military Pinout



## ASI TO DSCC PART NUMBER CROSS REFERENCE

### Package Designator Q

<u>ASI Part #</u>	<u>SMD Part #</u>
AS8S512K32Q-12/Q	5962-9461120HMX
AS8S512K32Q-15/Q	5962-9461119HMX
AS8S512K32Q-17/Q	5962-9461110HMX
AS8S512K32Q-20/Q	5962-9461109HMX
AS8S512K32Q-25/Q	5962-9461108HMX
AS8S512K32Q-35/Q	5962-9461107HMX
AS8S512K32Q-45/Q	5962-9461106HMX
AS8S512K32Q-55/Q	5962-9461105HMX
AS8S512K32Q-12/Q	5962-9461118HMX
AS8S512K32Q-15/Q	5962-9461117HMX
AS8S512K32Q-17/Q	5962-9461116HMX
AS8S512K32Q-20/Q	5962-9461115HMX
AS8S512K32Q-25/Q	5962-9461114HMX
AS8S512K32Q-35/Q	5962-9461113HMX
AS8S512K32Q-45/Q	5962-9461112HMX
AS8S512K32Q-55/Q	5962-9461111HMX

### Package Designator P

<u>ASI Part #</u>	<u>SMD Part #</u>
AS8S512K32P-12/Q	5962-9461120HTA
AS8S512K32Q-15/Q	5962-9461119HTA
AS8S512K32P-17/Q	5962-9461110HTA
AS8S512K32P-20/Q	5962-9461109HTA
AS8S512K32P-25/Q	5962-9461108HTA
AS8S512K32P-35/Q	5962-9461107HTA
AS8S512K32P-45/Q	5962-9461106HTX
AS8S512K32P-55/Q	5962-9461105HTX
AS8S512K32Q-15/Q	5962-9461117HTA
AS8S512K32P-12/Q	5962-9461118HTA
AS8S512K32P-17/Q	5962-9461116HTA
AS8S512K32P-20/Q	5962-9461115HTA
AS8S512K32P-25/Q	5962-9461114HTA
AS8S512K32P-35/Q	5962-9461113HTA
AS8S512K32P-45/Q	5962-9461112HTA
AS8S512K32P-55/Q	5962-9461111HTA

### Package Designator Q1

<u>ASI Part #</u>	<u>SMD Part #</u>
AS8S512K32Q1-12/Q	5962-9461120HAX
AS8S512K32Q1-15/Q	5962-9461119HAX
AS8S512K32Q1-17/Q	5962-9461110HAX
AS8S512K32Q1-20/Q	5962-9461109HAX
AS8S512K32Q1-25/Q	5962-9461108HAX
AS8S512K32Q1-35/Q	5962-9461107HAX
AS8S512K32Q1-45/Q	5962-9461106HAX
AS8S512K32Q1-55/Q	5962-9461105HAX
AS8S512K32Q1-12/Q	5962-9461118HAX
AS8S512K32Q1-15/Q	5962-9461117HAX
AS8S512K32Q1-17/Q	5962-9461116HAX
AS8S512K32Q1-20/Q	5962-9461115HAX
AS8S512K32Q1-25/Q	5962-9461114HAX
AS8S512K32Q1-35/Q	5962-9461113HAX
AS8S512K32Q1-45/Q	5962-9461112HAX
AS8S512K32Q1-55/Q	5962-9461111HAX